



The Development of a Qualification Temperature Profile for Lead-Free Reflow Soldering and the Influence of the Peak Width on the Semiconductor Devices

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Outline:

**The Development of a Qualification Temperature Profile for
Lead-Free Reflow Soldering**

- Prerequisites and general Requirements
- Test Board Design
- Tolerances
- Peak Form and Width
- Measured Temperatures
- Device Classes
- The Qualification Profile

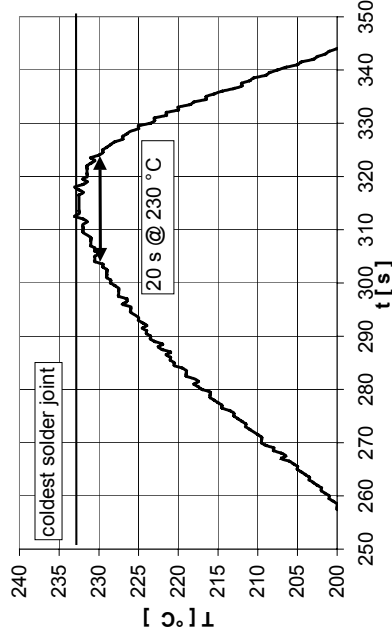
The Influence of the Peak Width on the Semiconductor Devices

- Description of the performed Experiment
- Reflow Profiles
- SAM Results

Temperature and Time Requirements at Coldest Solder Joint

- General requirement to achieve a reliable solder joint, while reducing the heat impact on the components and the printed circuit board:
⇒ **minimum 20 s @ 230 °C (corresponds to 1 s @ 233 °C)**
- Comparison between SnPb and SnAgCu technology:

SnPb: $T_{\text{liquid}} = 183\text{ °C}$ $T_{\text{min}} = 203\text{ °C}$ $\Delta T = 20\text{ K}$
SnAgCu: $T_{\text{liquid}} = 217\text{ °C}$ $T_{\text{min}} = 230\text{ °C}$ $\Delta T = 13\text{ K}$



Qualification Temperature Profile for Lead-Free Reflow Soldering

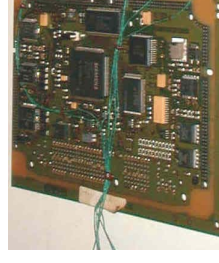
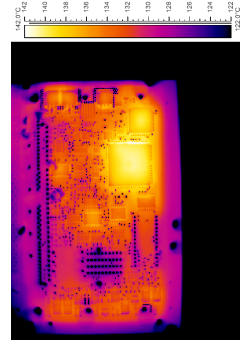
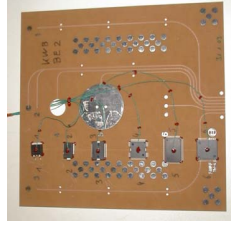
Equipment and Automotive Mass Production Conditions

- Moderate range of package sizes on typical board
- Transportation speed:
realistic production line speed of 850 mm/min (33 inch/min)
- Reflow soldering equipment:
only 4 of 7 reflow furnace suppliers are able to fulfill the requirements
for the T-profile with full convection, > 10 zone furnaces, N₂
atmosphere (status 2003)

Qualification Temperature Profile for Lead-Free Reflow Soldering

Test Board Design

- Material: Polyimide resin (T_g : 260 °C)
- 6 measuring points on each type of board
 - type I board: coldest solder joint + 5 x PCB surface
 - type II board: 6 x on top of device package
- Coldest solder joint:
 - coldest solder joint on test board represents the coldest solder joint on serial boards (thermal mass)
 - definition by measurements on serial boards using thermographic methods and experience



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Tolerances of Temperature Measurement and Furnace

- Temperature measurement:
- Temperature measurement done central on top of the packages
 - Selected thermocouples (NiCrNi)
 - Standardized preparation of thermocouples
 - Measurement and preparation accuracy

± 1.0 K

Thermocouples with evaluation unit:

± 0.5 K

Assembly of thermocouples (best case):

Tolerance of temperature measurement: $\Delta T_{\text{meas}} = \pm 1.5 \text{ K}$

Tolerances of Temperature Measurement and Furnace

- Consideration of process tolerances necessary for serial production of automotive products
Furnace tolerances:
State of furnace loading (min. / max. loading): **± 0.5 K**
Long term stability (5 σ tolerance): **± 2.5 K**
Total tolerance of temperature measurement and furnace:
Gaussian error propagation theorem possible (independent tolerances):

Loading of the furnace: **± 0.5 K**
Long term stability of the furnace: **± 2.5 K**
Temperature measurement ΔT_{meas} : **± 1.5 K**

Tolerance of measurement and furnace: $\Delta T_{\text{mf}} = \pm 3.0 \text{ K}$

Temperature Correction based on Test Board Design

- Longitudinal temperature profile dependent on test board design (**lowest** temperature in the middle of the board)
- Transverse temperature profile according to furnace suppliers
- Thermal mass (coldest solder joint) on test board includes both temperature corrections
- For upper tolerance of temperature window both corrections have to be considered

Transverse temperature correction: + 2.0 K

Longitudinal temperature correction: + 1.5 K

Temperature correction dep. on position: $\Delta T_{\text{pos}} = + 2.0$ to 3.5 K

Qualification Temperature Profile for Lead-Free Reflow Soldering

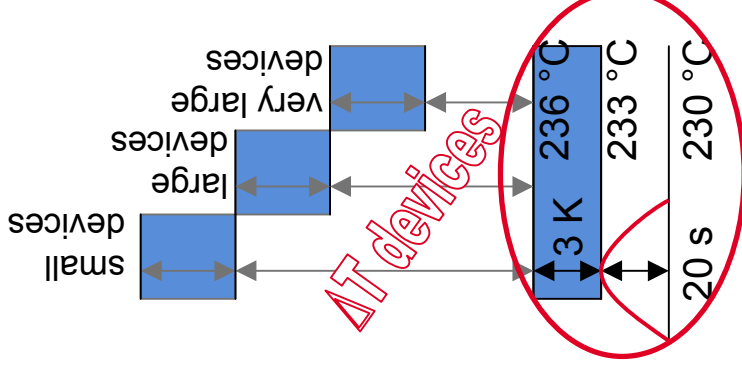
Addition of Board and Process Tolerances

- Starting point: 20 sec @ 230 °C, i. e. 1 s @ 233 °C based on experience and measurements
- Test board and furnace tolerances

↑ Due to $\Delta T_{mf} = \pm 3.0 \text{ K}$, the furnace has to be adjusted 3 K higher!
↑ Coldest solder joint has to be profiled at 236 °C!

- Temperature split of devices
- position dependent upper tolerance

↑ $\Delta T_{mf} + \Delta T_{pos} = 5 \text{ K to } 6.5 \text{ K}$



Qualification Temperature Profile for Lead-Free Reflow Soldering

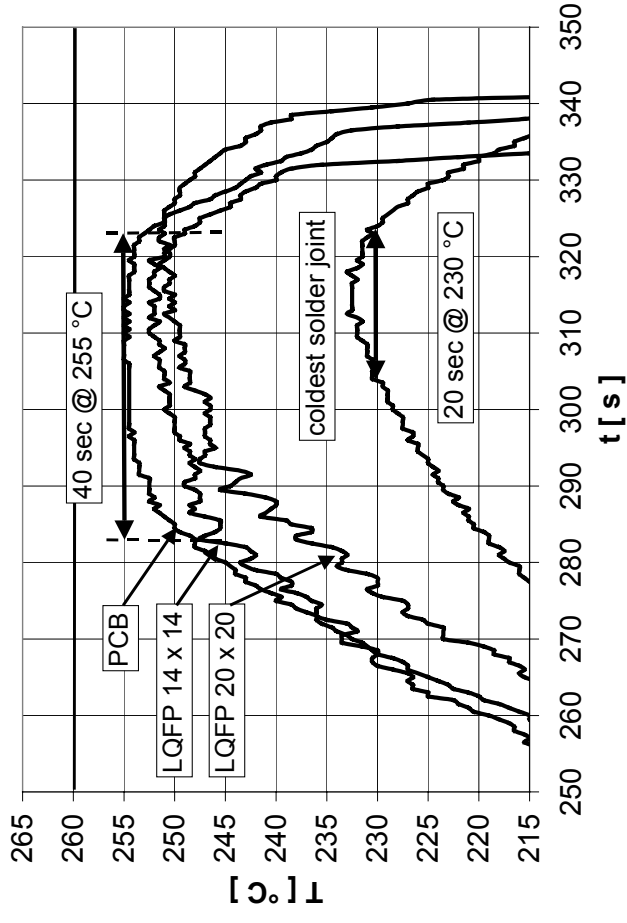
Peak Form and Width: Device Classification (Small Components < 260 °C)

- Hat type profile necessary to obtain:

- coldest solder joint
20 s @ 230 °C
- small components
 $T_{Peak} \leq 260 \text{ °C}$

- Necessary times
 $t @ T_{Peak} - 5 \text{ K}$:

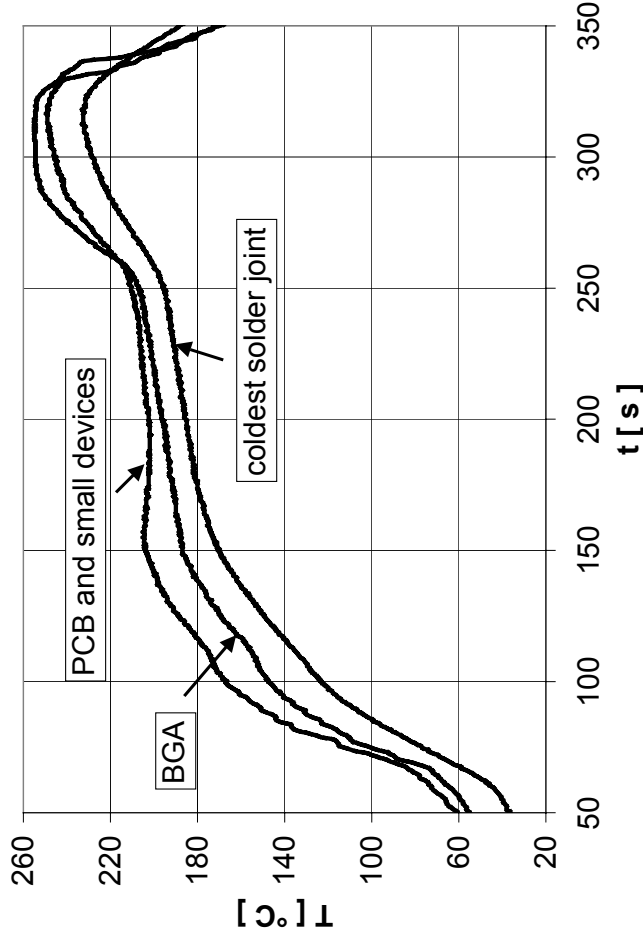
T_{Peak}	260 °C
$t @ T_{Peak} - 5K$	40s@255°C
T_{Peak}	250 °C
$t @ T_{Peak} - 5K$	30s@245°C
T_{Peak}	245 °C
$t @ T_{Peak} - 5K$	30s@240°C



Qualification Temperature Profile for Lead-Free Reflow Soldering

Measurements using Test Board

- Investigation of 20 different packages including tolerances
- All thermocouples mounted on top of the packages (central)
- Transportation speed: 850 mm/min (33 inch/min)



Qualification Temperature Profile for Lead-Free Reflow Soldering

Peak Temperatures of Devices

- Measured values and final values with tolerances
- Tolerances:
 $\Delta T_{mf} = \pm 3.0 \text{ K}$
 $\Delta T_{pos} = + 2.0 \text{ to } 3.5 \text{ K}$
- 3 classes of devices
 245 °C, 250 °C, 255 °C
- Distance to coldest solder joint
 of measured values (ΔT):
 4 K (large devices)
 9 K (small devices)
 14 K (distance to printed circuit board)

package (measurement on top of package)	measurement	final values with tolerances
	[°C]	[°C]
coldest solder joint	233,0	236,0
PLCC 84 (30 x 30)	232,5	241,0
QFP160 (28 x 28)	233,5	242,0
PLCC 68 (24 x 24)	233,5	242,5
PLCC 44 (17 x 17)	234,0	242,5
PLCC 52 (19 x 19)	234,0	243,0
DO218	236,0	244,5
MO-166	237,0	246,0
QFP-exposed pad (20 x 14)	237,5	246,0
SO28	237,5	246,0
PLCC 28 (12 x 12)	238,0	246,0
QFP144 (28 x 28)	237,0	246,5
MO-188 (14 x 14)	237,5	247,0
QFP80 (20x14)	238,5	247,0
TO 263	239,5	247,5
SO 44 XL	240,0	248,0
QFP 80 (14 x 14)	240,5	248,5
BGA (24 x 24)	240,5	249,5
LQFP-MS026 (20x20)	242,0	251,5
LQFP 100 (14 x 14)	243,5	252,5
temperature on pwb	247,0	255,0

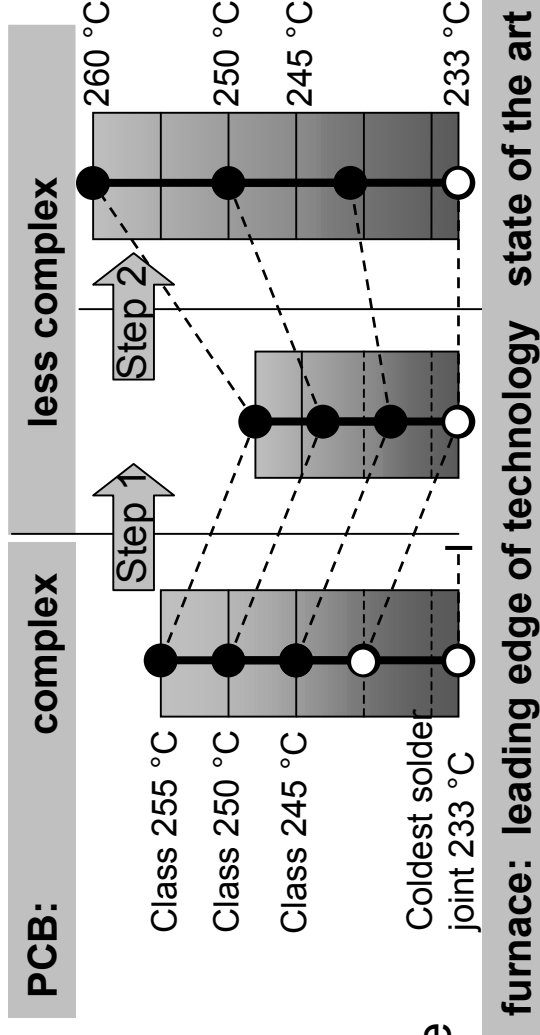
Qualification Temperature Profile for Lead-Free Reflow Soldering

Peak Temperature 260 °C for small Components

- Benefit of qualifying at 260 °C: Less complex boards can be soldered on state of the art reflow furnaces (actual equipment)
- Qualification of small devices at 260 °C is very common, other devices will stay in their class (250 °C, 245 °C).

Step 1:
Reduction of ΔT due to less complexity of the board

Step 2:
Enlargement of ΔT between devices because of change to state of the art furnace (less powerful furnace)



Qualification Temperature Profile for Lead-Free Reflow Soldering

Peak Temperature: Device Classification

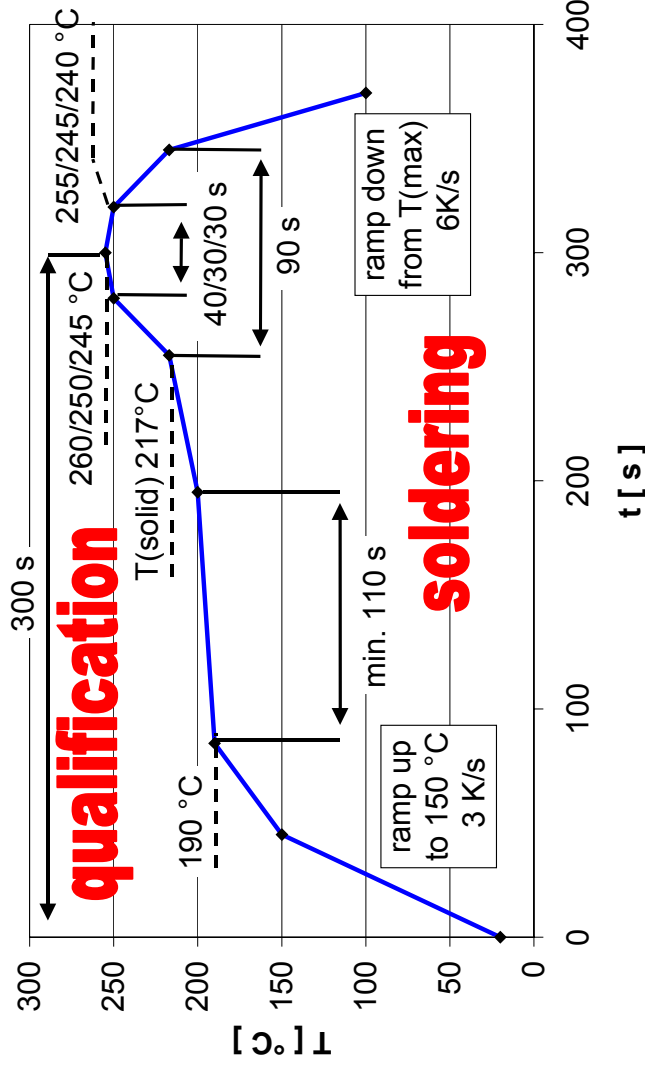
- From a physical point of view the heat capacity and heat conductivity should be the measure for device classification
- But volume and thickness are taken for simplification reasons. This is possible for devices with similar composition (molded components)

thickness\volume	< 350 mm ³	350 - 2000 mm ³	> 2000 mm ³
< 1,6 mm	260 (-0) °C	260 (-0) °C	260 (-0) °C
1,6 - 2,5 mm	260 (-0) °C	250 (-0) °C	250 (-0) °C
> 2,5 mm	250 (-0) °C	250 (-0) °C	245 (-0) °C

- Due to repair reasons all BGAs 260 °C

Qualification Temperature Profile for Lead-Free Reflow Soldering

Lead-free Reflow Temperature Profile for MSL Classification (Figure)



- **Qualification profile** with minimum values for temperatures, times, ramp up and ramp down rates. Devices have to be soldered at least 3 times
- The shown graph represents the limiting line between suppliers and manufacturers

Qualification Temperature Profile for Lead-Free Reflow Soldering

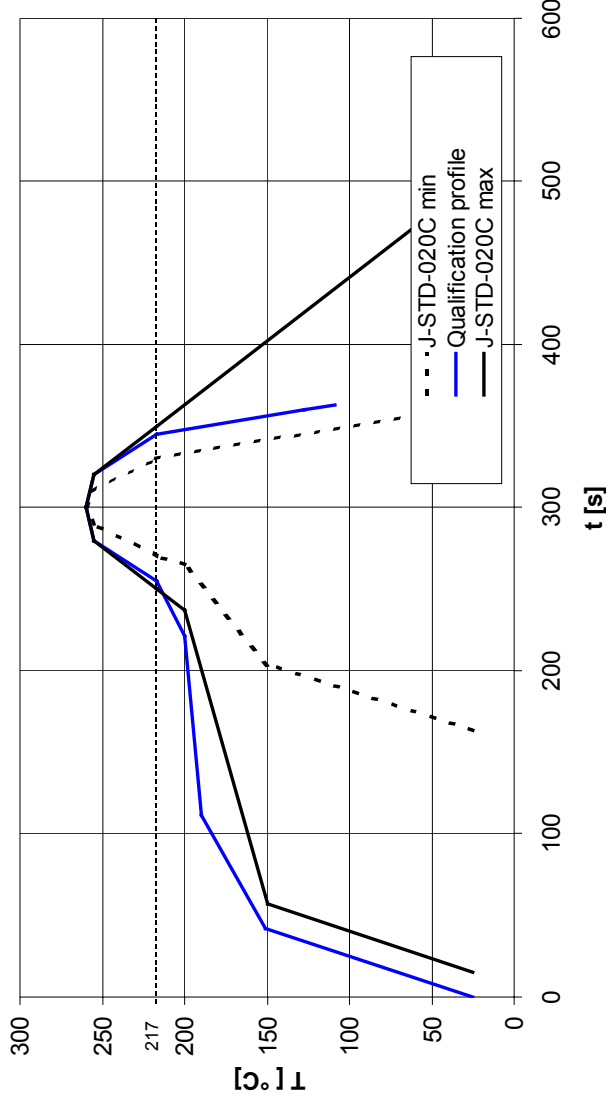
Lead-free Reflow Temperature Profile for MSL Classification (Table)

Profile Features	Small Devices	Large Devices	Very Large Devices
preheat			
ramp-up rate to 150 °C	min. 3 K/s (average value over 10 s)		
time from 190°C to 200°C	min. 110 s		
peak			
ramp-up rate from 200°C to T _{peak}	0,5 K/s - 3 K/s (average value over 10 s)		
time above T _{solidus} (min. 217 °C)	min. 90 s		
peak temperature T _{peak}	260 (-0) °C	250 (-0) °C	245 (-0) °C
time above T _{peak} - 5 K	min. 40 s	min. 30 s	min. 30 s
cooling			
ramp-down rate from T _{solidus} (min. 217	min. 6 K/s (average value over 10 s)		
general			
time 25 °C to T _{peak}	min. 300 s		

- Qualification profile with min. values for temperatures, times and ramps
- Device qualification temperature profile at the component supplier has to stay above these values, while during soldering the electronic assembler has to stay below these values

Qualification Temperature Profile for Lead-Free Reflow Soldering

Comparison between presented Qualification Profile and J-STD-020C



- Devices qualified according to J-STD-020C **max** will presumably pass the proposed qualification profile
- Qualification according to J-STD-020C **min** is not sufficient for real assembly processes

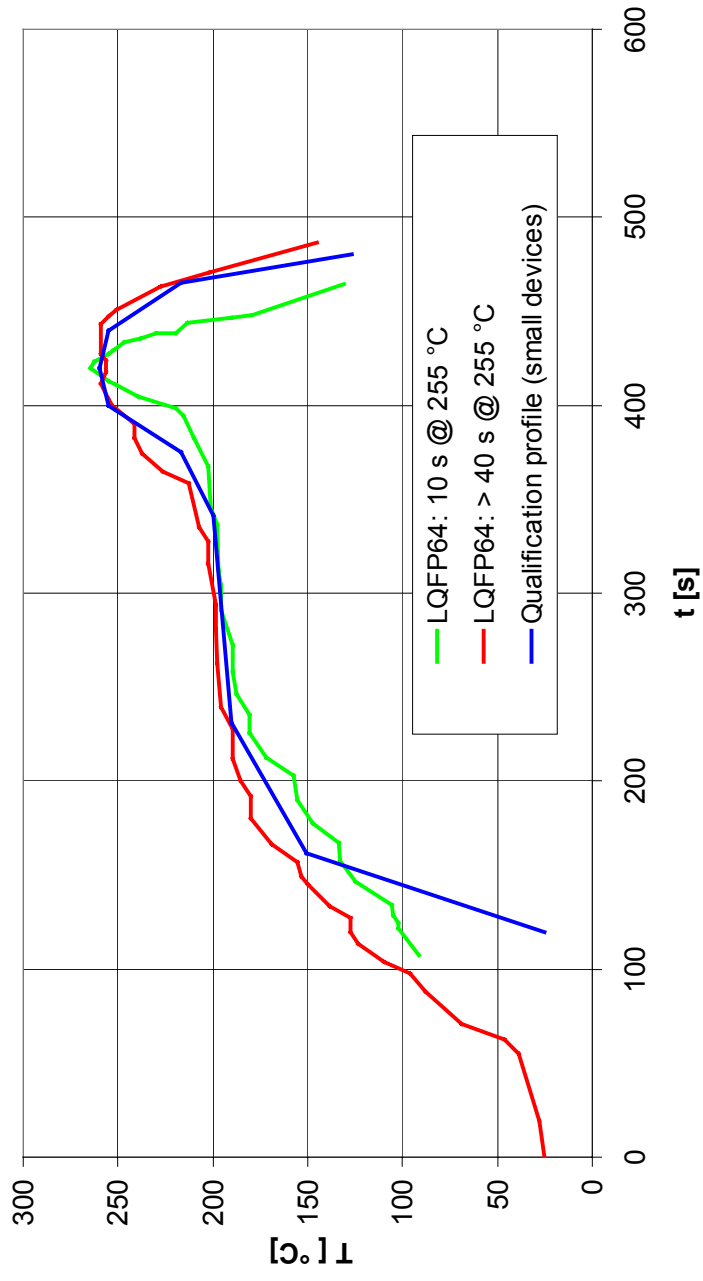
Description of the performed Experiment

- Investigated samples: LQFP100, LQFP64, TSSOP 38 (3 different suppliers, different mold compounds, qualified or in qualification for lead-free process)
- Preconditioning for MSL = 3 (drying: 24 h / 125 °C, moisture soak: 192 h / 30 °C / 60 % relative humidity)
- 1 x reflow soldering with different peak widths: 10 s, 20 s, 30 s, 40 s (30 devices each)
- SAM (scanning acoustic microscopy)

Influence of the Peak Width on the Semiconductor Devices

Reflow Profiles

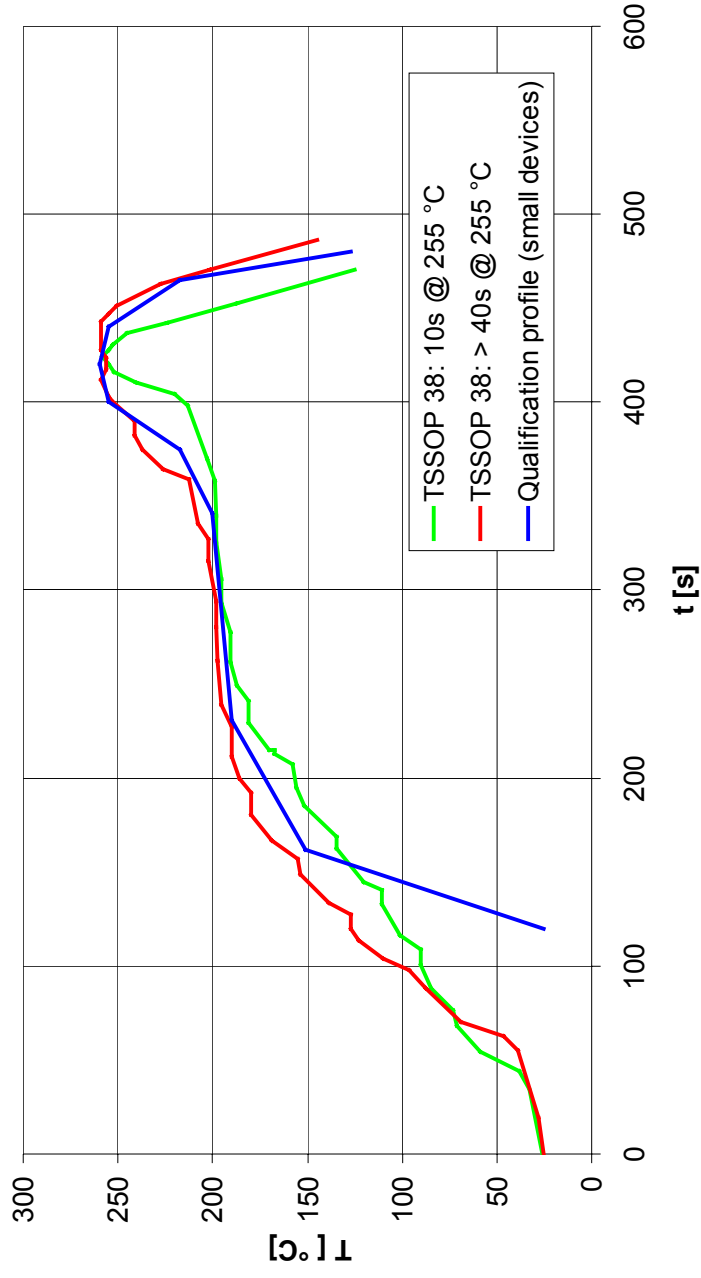
LQFP100/64



Influence of the Peak Width on the Semiconductor Devices

Reflow Profiles

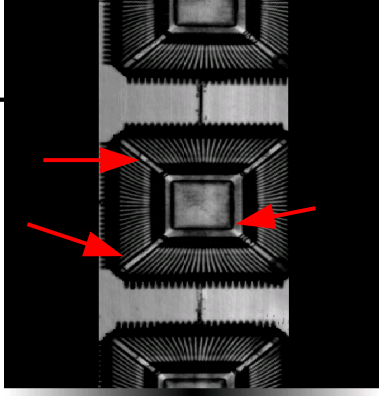
TSSOP 38



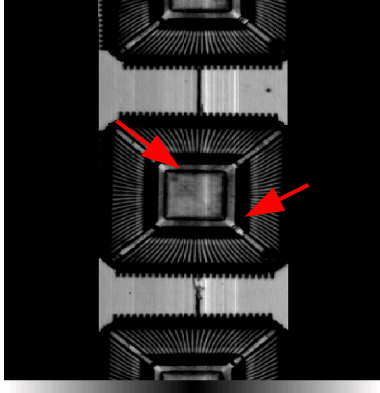
Influence of the Peak Width on the Semiconductor Devices

SAM Results: LQFP100

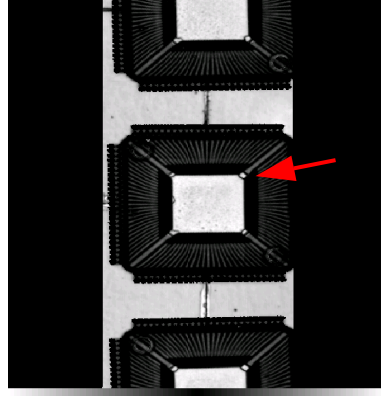
Top side: complete delamination of the die paddle; tie bar shows partial delamination (not critical)



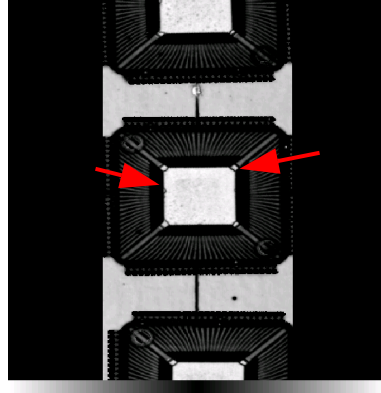
T_{peak} : 260.0 °C
 $t_{@255\text{ °C}}$: 9 s



Bottom side: partial delamination of the die paddle (not critical)



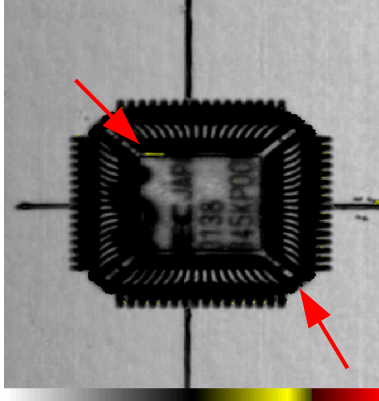
T_{peak} : 260.0 °C
 $t_{@255\text{ °C}}$: 45 s



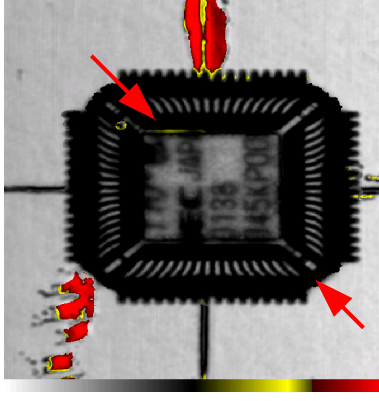
Influence of the Peak Width on the Semiconductor Devices

SAM Results: LQFP64

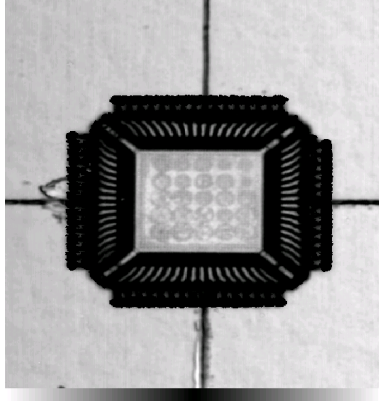
Top side: Partial delamination of the die paddle and tie bar (not critical)



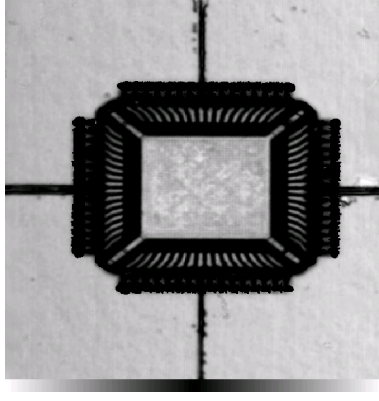
T_{peak} : 261.5 °C
 $t_{@255\text{ °C}}$: 12 s



Bottom side: no delaminations found



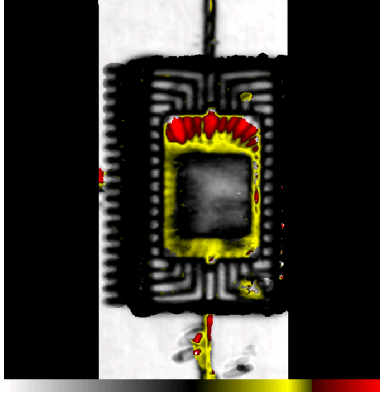
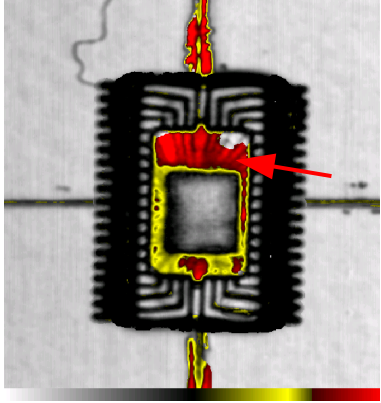
T_{peak} : 259.5 °C
 $t_{@255\text{ °C}}$: 41 s



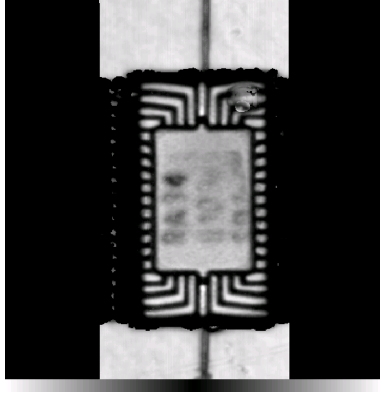
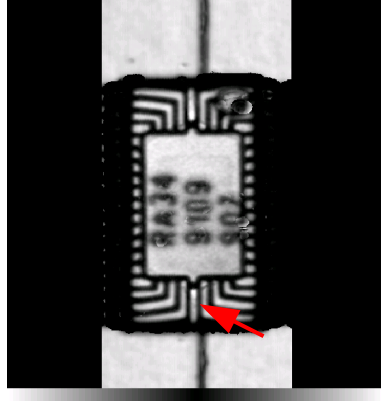
Influence of the Peak Width on the Semiconductor Devices

SAM Results: TSSOP 38

Top side: Complete delamination of the die paddle and tie bar (not critical)



Bottom side: partial delamination of some leadframe fingers (not critical)



Conclusions

- **Qualification temperature profile was developed to cover automotive requirements concerning reliability of the solder joint**
- **Using presented limiting profile prevents devices from harmful, unexpected stress during real, also non-automotive assembly processes**
- **No influence of the peak width on the delamination of the semiconductors was found**
- **Influence of temperature gradient during ramp up and ramp down on the delamination and reliability of the devices should be investigated**
- **Similar investigations for passive, non-molded devices are necessary**